Ultra Series™ 水晶発振器
Si541 データ・シート

超低ジッタ・デュアル任意周波数 XO（125 fs）、0.2 ～ 1500 MHz

Si541 Ultra Series™ 発振器は Silicon Labs の高度な第 4 世代 DSPLL® テクノロジーを使用し、超低ジッタ、低位相ノイズのクロックを選択可能な 2 つの周波数で実現します。デバイスは、0.2 ～ 1500 MHz の選択可能な任意の 2 つの周波数に対応するよう、1 ppb 未満の分解能で工場出荷時にプログラムされ、動作範囲全体の整数周波数と分数周波数両方で非常に低いジッタを維持します。Si541 は優れた信頼性と周波数の安定性を提供し、経年的な性能も保証されています。オンチップの電源フィルタリングにより、業界最先端の電源ノイズ除去性能を実現しており、スィッチング方式の電源を使用するノイズの多いシステムで、低ジッタ・クロックの生成タスクを簡素化します。Si541 は業界標準のフットプリントで提供され、サプライ・チェーンが非常に簡素化されているため、Silicon Labs はカスタム周波数のサンプルを受注後 1 ～ 2 週間で出荷できます。出力周波数ごとに異なる水晶が必要な従来の XO とは違い、Si541 は 1 つの簡単な水晶と DSPLL IC ベースのアプローチで必要な出力周波数を生成します。このプロセスでは、各デバイスの 100% 電気的試験も保証しています。Si541 は、周波数、出力形式、OE ピン配列/極性など、幅広いユーザ仕様に合わせて工場出荷時に構成できます。カスタム発振器に伴う長いリード・タイムを排除するために、固有の構成は工場出荷時にプログラムされています。

主な機能

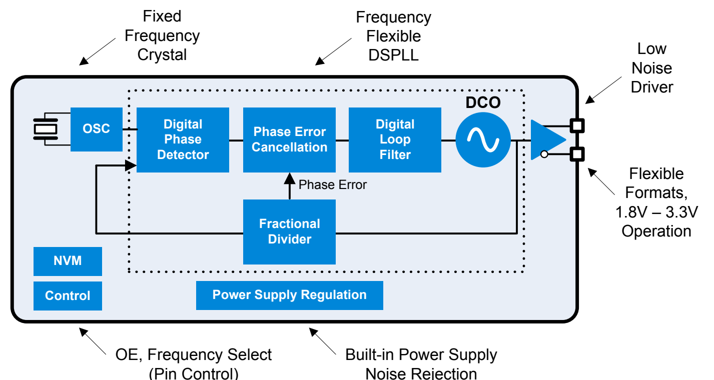
- 0.2 MHz ～ 1500 MHz の選択可能な任意の 2 つの周波数で利用可能
- 超低ジッタ：125 fs（標準値）RMS（12 kHz ～ 20 MHz）
- 優れた PSNR および電源ノイズ耐性: -80dBc（標準値）
- 7 ppm 安定性オプション（-40 ～ 85 °C）
- 同じ部品番号から、3.3 V、2.5 V および 1.8 V V_{DD} の電源動作
- LVPECL、LVDS、CML、HCSL、CMOS、およびデュアル CMOS 出力オプション
- 2.5x3.2、3.2x5、5x7 mm パッケージ・オプション
- 1 ～ 2 週間のリード・タイムで任意のカスタム周波数を提供

アプリケーション

- 100G/200G/400G OTN、コヒーレント光学
- 10G/40G/100G 光イーサネット
- 3G-SDI/12G-SDI/24G-SDI 放送ビデオ
- サーバ、スイッチ、ストレージ、NIC、検索の高速化
- テストおよび測定
- クロックおよびデータ・リカバリ
- FPGA/ASIC クロッキング

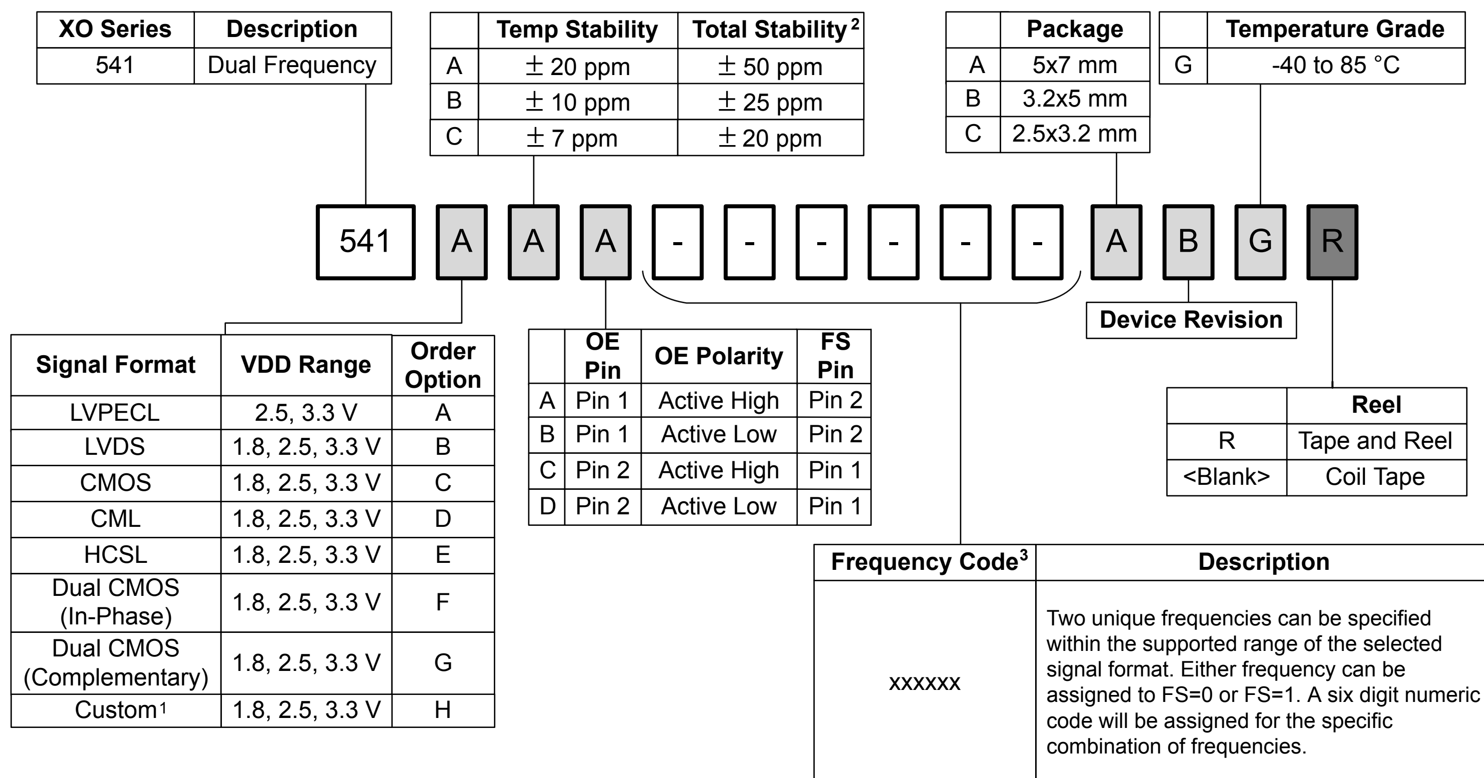
ピン配置

ピン番号	説明
1、2	*発注オプションにより選択可能* OE = 出力イネーブル、FS = 周波数選択
3	GND = グランド
4	CLK+ = クロック出力
5	CLK- = 相補クロック出力。CMOS には未使用。
6	VDD = 電源



1. Ordering Guide

The Si541 XO supports a variety of options including frequency, output format, and OE pin location/polarity, as shown in the chart below. Specific device configurations are programmed into the part at time of shipment, and samples are available in 1-2 weeks. Silicon Laboratories provides an online part number configuration utility to simplify this process. Refer to www.silabs.com/oscillators to access this tool and for further ordering instructions.



541 A A A - - - - - - A B G R

XO Series	Description
541	Dual Frequency

	Temp Stability	Total Stability[2]
A	± 20 ppm	± 50 ppm
B	± 10 ppm	± 25 ppm
C	± 7 ppm	± 20 ppm

	Package
A	5x7 mm
B	3.2x5 mm
C	2.5x3.2 mm

	Temperature Grade
G	-40 to 85 °C

Signal Format	VDD Range	Order Option
LVPECL	2.5, 3.3 V	A
LVDS	1.8, 2.5, 3.3 V	B
CMOS	1.8, 2.5, 3.3 V	C
CML	1.8, 2.5, 3.3 V	D
HCSL	1.8, 2.5, 3.3 V	E
Dual CMOS (In-Phase)	1.8, 2.5, 3.3 V	F
Dual CMOS (Complementary)	1.8, 2.5, 3.3 V	G
Custom[1]	1.8, 2.5, 3.3 V	H

	OE Pin	OE Polarity	FS Pin
A	Pin 1	Active High	Pin 2
B	Pin 1	Active Low	Pin 2
C	Pin 2	Active High	Pin 1
D	Pin 2	Active Low	Pin 1

Device Revision

	Reel
R	Tape and Reel
<Blank>	Coil Tape

Frequency Code[3]	Description
xxxxxx	Two unique frequencies can be specified within the supported range of the selected signal format. Either frequency can be assigned to FS=0 or FS=1. A six digit numeric code will be assigned for the specific combination of frequencies.

Notes:

1. Contact Silicon Labs for non-standard configurations.
2. Total stability includes temp stability, initial accuracy, load pulling, VDD variation, and 20 year aging at 70 °C.
3. Create custom part numbers at www.silabs.com/oscillators.

1.1 Technical Support

Frequently Asked Questions (FAQ)	www.silabs.com/Si541-FAQ
Oscillator Phase Noise Lookup Utility	www.silabs.com/oscillator-phase-noise-lookup
Quality and Reliability	www.silabs.com/quality
Development Kits	www.silabs.com/oscillator-tools

2. Electrical Specifications

Table 2.1. Electrical Specifications

V_{DD} = 1.8 V, 2.5 or 3.3 V ± 5%, T_A = –40 to 85 ºC

Parameter	Symbol	Test Condition/Comment	Min	Typ	Max	Unit
Temperature Range	T_A		–40	—	85	ºC
Frequency Range	F_{CLK}	LVPECL, LVDS, CML	0.2	—	1500	MHz
		HCSL	0.2	—	400	MHz
		CMOS, Dual CMOS	0.2	—	250	MHz
Supply Voltage	V_{DD}	3.3 V	3.135	3.3	3.465	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
Supply Current	I_{DD}	LVPECL (output enabled)	—	100	145	mA
		LVDS/CML (output enabled)	—	75	111	mA
		HCSL (output enabled)	—	80	125	mA
		CMOS (output enabled)	—	74	108	mA
		Dual CMOS (output enabled)	—	80	125	mA
		Tristate Hi-Z (output disabled)	—	64	100	mA
Temperature Stability		Frequency stability Grade A	–20	—	20	ppm
		Frequency stability Grade B	–10	—	10	ppm
		Frequency stability Grade C	–7	—	7	ppm
Total Stability[1]	F_{STAB}	Frequency stability Grade A	–50	—	50	ppm
		Frequency stability Grade B	–25	—	25	ppm
		Frequency stability Grade C	–20	—	20	ppm
Rise/Fall Time (20% to 80% V_{PP})	T_R/T_F	LVPECL/LVDS/CML	—	—	350	ps
		CMOS / Dual CMOS, (C_L = 5 pF)	—	0.5	1.5	ns
		HCSL, F_{CLK} >50 MHz	—	—	550	ps
Duty Cycle	D_C	All formats	45	—	55	%
Output Enable (OE) Frequency Select (FS)[2]	V_{IH}		0.7 × V_{DD}	—	—	V
	V_{IL}		—	—	0.3 × V_{DD}	V
	T_D	Output Disable Time, F_{CLK} >10 MHz	—	—	3	µs
	T_E	Output Enable Time, F_{CLK} > 10 MHz	—	—	20	µs
	T_{FS}	Settling Time after FS Change	—	—	10	ms
Powerup Time	t_{OSC}	Time from 0.9 × V_{DD} until output frequency (F_{CLK}) within spec	—	—	10	ms
Powerup VDD Ramp Rate	V_{RAMP}	Fastest VDD ramp allowed on startup	—	—	9	V/ms

Parameter	Symbol	Test Condition/Comment	Min	Typ	Max	Unit
LVPECL Output Option[3]	V_{OC}	Mid-level	V_{DD} – 1.42	—	V_{DD} – 1.25	V
	V_O	Swing (diff)	1.1	—	1.9	V_{PP}
LVDS Output Option[4]	V_{OC}	Mid-level (2.5 V, 3.3 V VDD)	1.125	1.20	1.275	V
		Mid-level (1.8 V VDD)	0.8	0.9	1.0	V
	V_O	Swing (F_{CLK} ≤ 1.4 GHz)	0.6	0.7	0.9	V_{PP}
		Swing (F_{CLK} > 1.4 GHz)	0.5	0.7	0.9	V_{PP}
HCSL Output Option[5]	V_{OH}	Output voltage high	660	750	850	mV
	V_{OL}	Output voltage low	–150	0	150	mV
	V_C	Crossing voltage	250	350	550	mV
CML Output Option (AC-Coupled)	V_O	Swing (diff)	0.6	0.8	1.0	V_{PP}
CMOS Output Option	V_{OH}	I_{OH} = 8/6/4 mA for 3.3/2.5/1.8 V VDD	0.85 × V_{DD}	—	—	V
	V_{OL}	I_{OL} = 8/6/4 mA for 3.3/2.5/1.8 V VDD	—	—	0.15 × V_{DD}	V

Notes:
1. Total Stability includes temperature stability, initial accuracy, load pulling, VDD variation, and aging for 20 yrs at 70 ºC.
2. OE includes a 50 kΩ pull-up to VDD for OE active high. Includes a 50 kΩ pull-down to GND for OE active low. FS includes a 50 kΩ pull-up to VDD.
3. 50 Ω to V_{DD} – 2.0 V.
4. R_{term} = 100 Ω (differential).
5. 50 Ω to GND.

Table 2.2. Clock Output Phase Jitter and PSNR

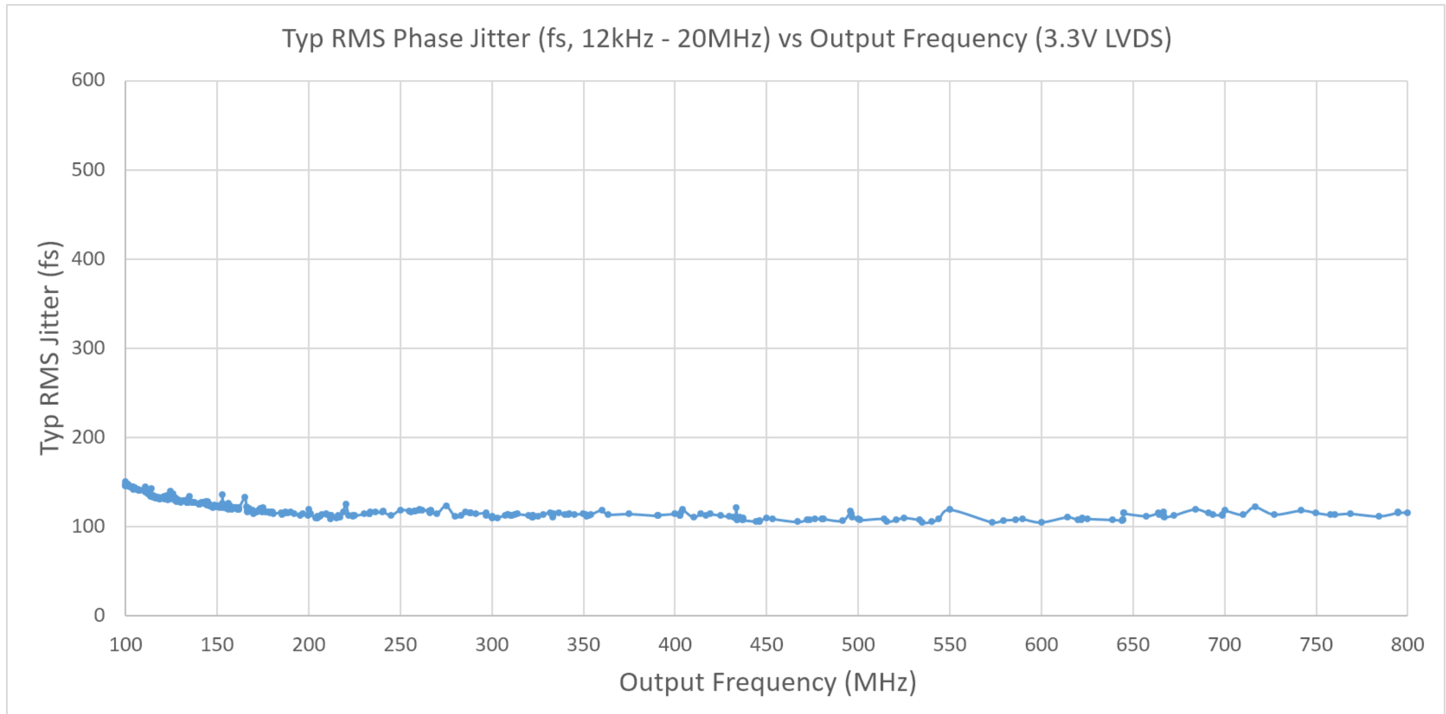
V_{DD} = 1.8 V, 2.5 or 3.3 V ± 5%, T_A = –40 to 85 ºC

Parameter	Symbol	Test Condition/Comment	Min	Typ	Max	Unit
Phase Jitter (RMS, 12kHz - 20MHz)[1] 2.5 x 3.2 mm, 3.2 x 5 mm, F_{CLK} ≥ 100 MHz	ϕ_J	Differential Formats	—	125	200	fs
		CMOS, Dual CMOS	—	200	—	fs
Phase Jitter (RMS, 12kHz - 20MHz)[1] 5 x 7 mm, F_{CLK} ≥ 100 MHz		Differential Formats	—	150	200	fs
		CMOS, Dual CMOS	—	200	—	fs
Spurs Induced by External Power Supply Noise, 50 mVpp Ripple. LVDS 156.25 MHz Output	PSNR	100 kHz sine wave	—	-83	—	dBc
		200 kHz sine wave	—	-83	—	
		500 kHz sine wave	—	-82	—	
		1 MHz sine wave	—	-85	—	

Note:
1. Guaranteed by characterization. Jitter inclusive of any spurs.

Table 2.3. 3.2 x 5 mm Clock Output Phase Noise (Typical, 50ppm Total Stability Option)

Offset Frequency (f)	156.25 MHz LVDS	200 MHz LVDS	644.53125 MHz LVDS	Unit
100 Hz	–110	–107	–99	dBc/Hz
1 kHz	–121	–120	–109	
10 kHz	–132	–130	–121	
100 kHz	–139	–137	–127	
1 MHz	–151	–149	–138	
10 MHz	–160	–161	–155	
20 MHz	–161	–162	–157	
Offset Frequency (f)	**156.25 MHz LVPECL**	**200 MHz LVPECL**	**644.53125 MHz LVPECL**	**Unit**
100 Hz	–113	–110	–100	dBc/Hz
1 kHz	–123	–120	–110	
10 kHz	–133	–130	–119	
100 kHz	–139	–137	–127	
1 MHz	–151	–149	–138	
10 MHz	–162	–166	–156	
20 MHz	–163	–167	–157	



Phase jitter measured with Agilent E5052 using a differential-to-single ended converter (balun or buffer). Measurements collected for >700 commonly used frequencies. Phase noise plots for specific frequencies are available using our free, online Oscillator Phase Noise Lookup Tool at www.silabs.com/oscillators.

Figure 2.1. Phase Jitter vs. Output Frequency

Table 2.4. Environmental Compliance and Package Information

Parameter	Test Condition
Mechanical Shock	MIL-STD-883, Method 2002
Mechanical Vibration	MIL-STD-883, Method 2007
Solderability	MIL-STD-883, Method 2003
Gross and Fine Leak	MIL-STD-883, Method 1014
Resistance to Solder Heat	MIL-STD-883, Method 2036
Moisture Sensitivity Level (MSL): 3.2 x 5, 5 x 7 packages	1
Moisture Sensitivity Level (MSL): 2.5 x 3.2 package	2
Contact Pads: 3.2x5, 5x7 packages	Au/Ni (0.3 - 1.0 µm / 1.27 - 8.89 µm)
Contact Pads: 2.5x3.2 packages	Au/Pd/Ni (0.03 - 0.12 µm / 0.1 - 0.2 µm / 3.0 - 8.0 µm)

Note:

1. For additional product information not listed in the data sheet (e.g. RoHS Certifications, MDDS data, qualification data, REACH Declarations, ECCN codes, etc.), refer to our "Corporate Request For Information" portal found here: www.silabs.com/support/quality/Pages/RoHSInformation.aspx.

Table 2.5. Thermal Conditions

Max Junction Temperature = 125° C

Package	Parameter	Symbol	Test Condition	Value	Unit
2.5 x 3.2 mm 6-pin DFN	Thermal Resistance Junction to Ambient	Θ_{JA}	Still Air, 85 °C	80	ºC/W
	Thermal Parameter Junction to Board	Ψ_{JB}	Still Air, 85 °C	39	ºC/W
	Thermal Parameter Junction to Top Center	Ψ_{JT}	Still Air, 85 °C	17	ºC/W
3.2 × 5 mm 6-pin CLCC	Thermal Resistance Junction to Ambient	Θ_{JA}	Still Air, 85 °C	55	ºC/W
	Thermal Parameter Junction to Board	Ψ_{JB}	Still Air, 85 °C	20	ºC/W
	Thermal Parameter Junction to Top Center	Ψ_{JT}	Still Air, 85 °C	20	ºC/W
5 × 7 mm 6-pin CLCC	Thermal Resistance Junction to Ambient	Θ_{JA}	Still Air, 85 °C	53	ºC/W
	Thermal Parameter Junction to Board	Ψ_{JB}	Still Air, 85 °C	26	ºC/W
	Thermal Parameter Junction to Top Center	Ψ_{JT}	Still Air, 85 °C	26	ºC/W

Note:

1. Based on PCB Dimensions: 4.5" x 7", PCB Thickness: 1.6 mm, Number of Cu Layers: 4.

Table 2.6. Absolute Maximum Ratings[1]

Parameter	Symbol	Rating	Unit
Maximum Operating Temp.	T_{AMAX}	95	ºC
Storage Temperature	T_S	–55 to 125	ºC
Supply Voltage	V_{DD}	–0.5 to 3.8	ºC
Input Voltage	V_{IN}	–0.5 to V_{DD} + 0.3	V

Parameter	Symbol	Rating	Unit
ESD HBM (JESD22-A114)	HBM	2.0	kV
Solder Temperature[2]	T_{PEAK}	260	ºC
Solder Time at T_{PEAK}[2]	T_P	20–40	sec

Notes:

1. Stresses beyond those listed in this table may cause permanent damage to the device. Functional operation specification compliance is not implied at these conditions. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. The device is compliant with JEDEC J-STD-020.

3. Dual CMOS Buffer

Dual CMOS output format ordering options support either complementary or in-phase signals for two identical frequency outputs. This feature enables replacement of multiple XOs with a single Si541 device.

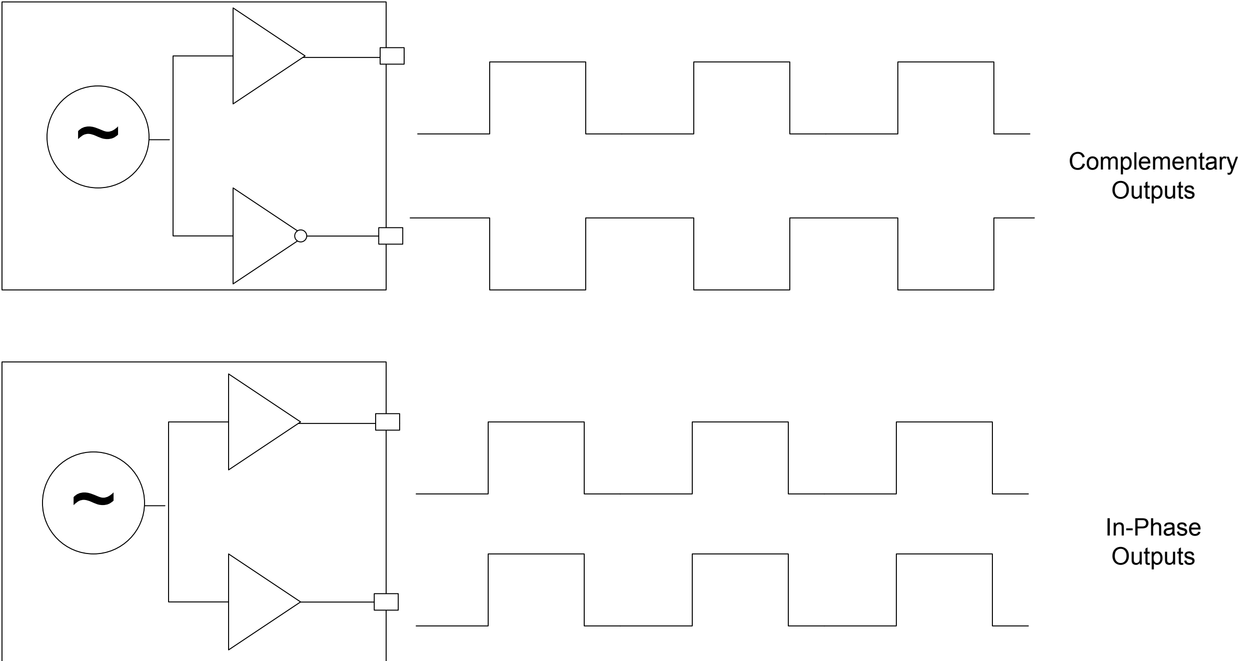


Figure 3.1. Integrated 1:2 CMOS Buffer Supports Complementary or In-Phase Outputs

4. Recommended Output Terminations

The output drivers support both AC-coupled and DC-coupled terminations as shown in figures below.

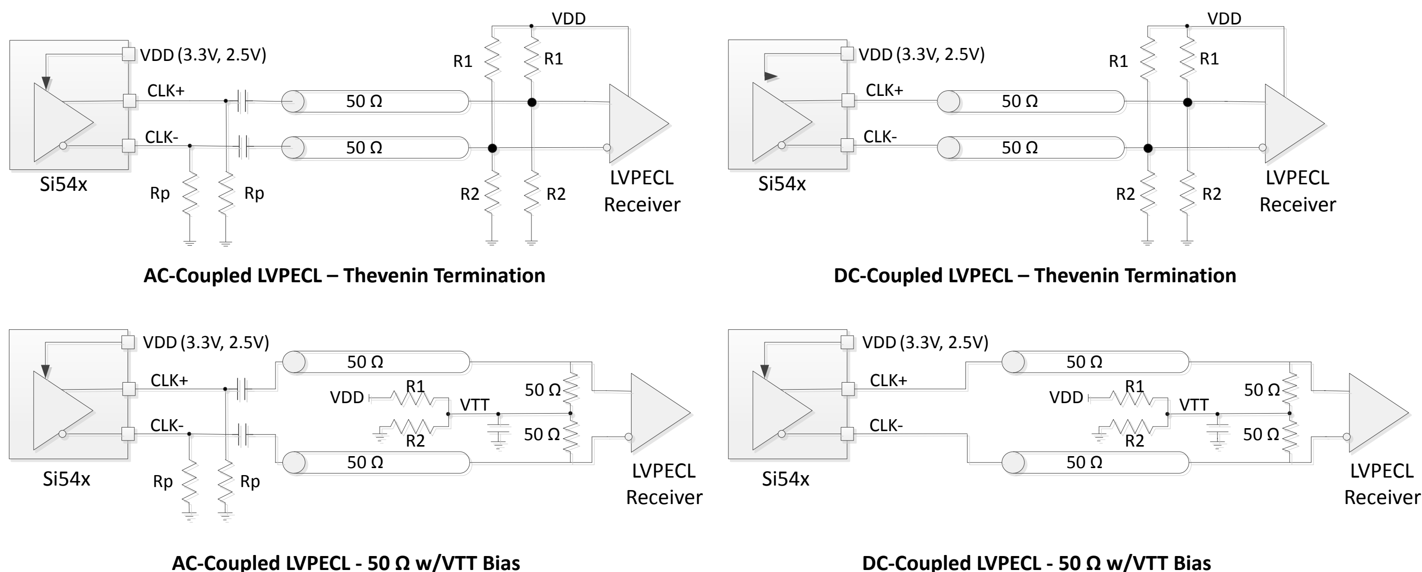


Figure 4.1. LVPECL Output Terminations

AC Coupled LVPECL Termination Resistor Values			
VDD	R1	R2	Rp
3.3 V	127 Ω	82.5 Ω	130 Ω
2.5 V	250 Ω	62.5 Ω	90 Ω

DC Coupled LVPECL Termination Resistor Values		
VDD	R1	R2
3.3 V	127 Ω	82.5 Ω
2.5 V	250 Ω	62.5 Ω

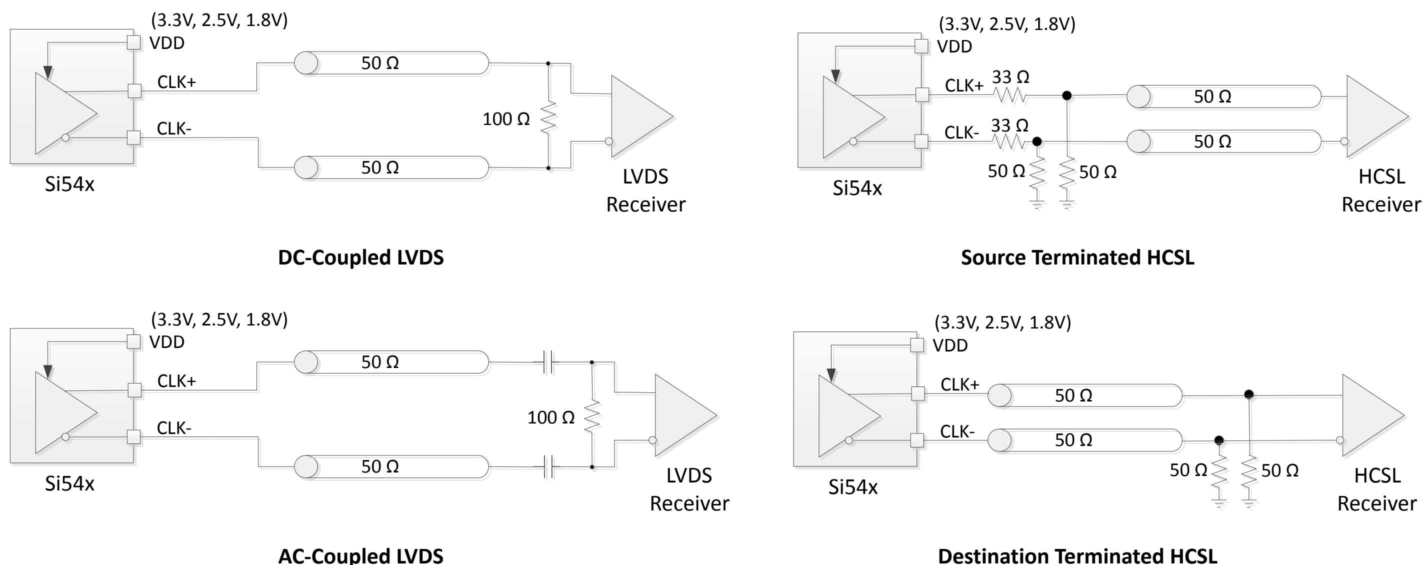


Figure 4.2. LVDS and HCSL Output Terminations

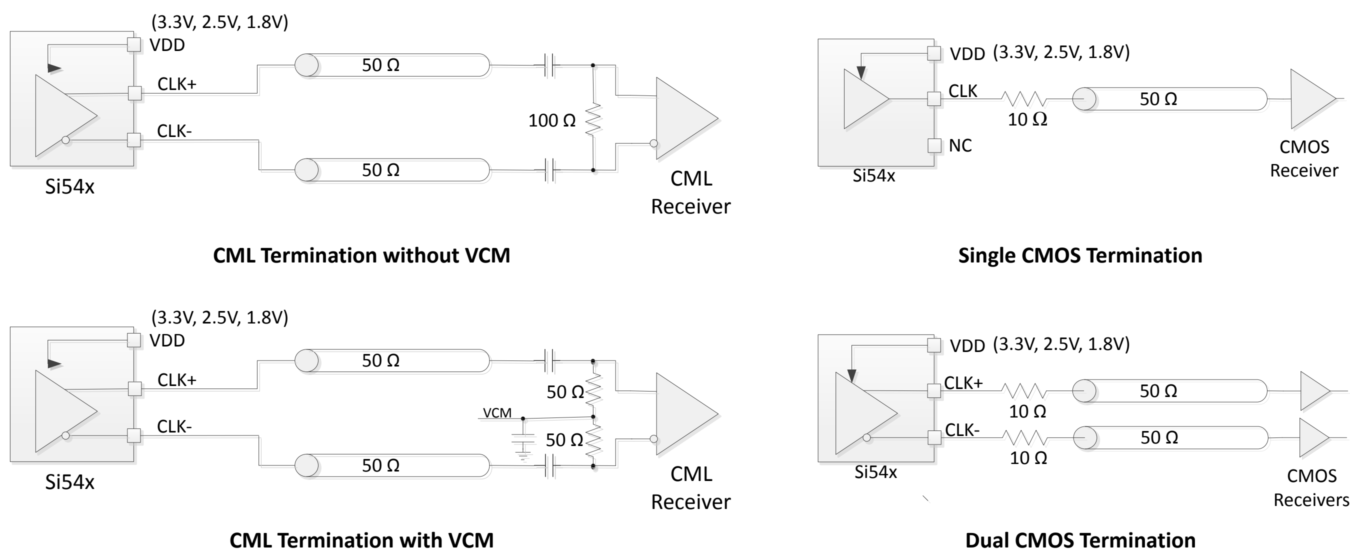


Figure 4.3. CML and CMOS Output Terminations

5. Package Outline

5.1 Package Outline (5×7 mm)

The figure below illustrates the package details for the 5×7 mm Si541. The table below lists the values for the dimensions shown in the illustration.

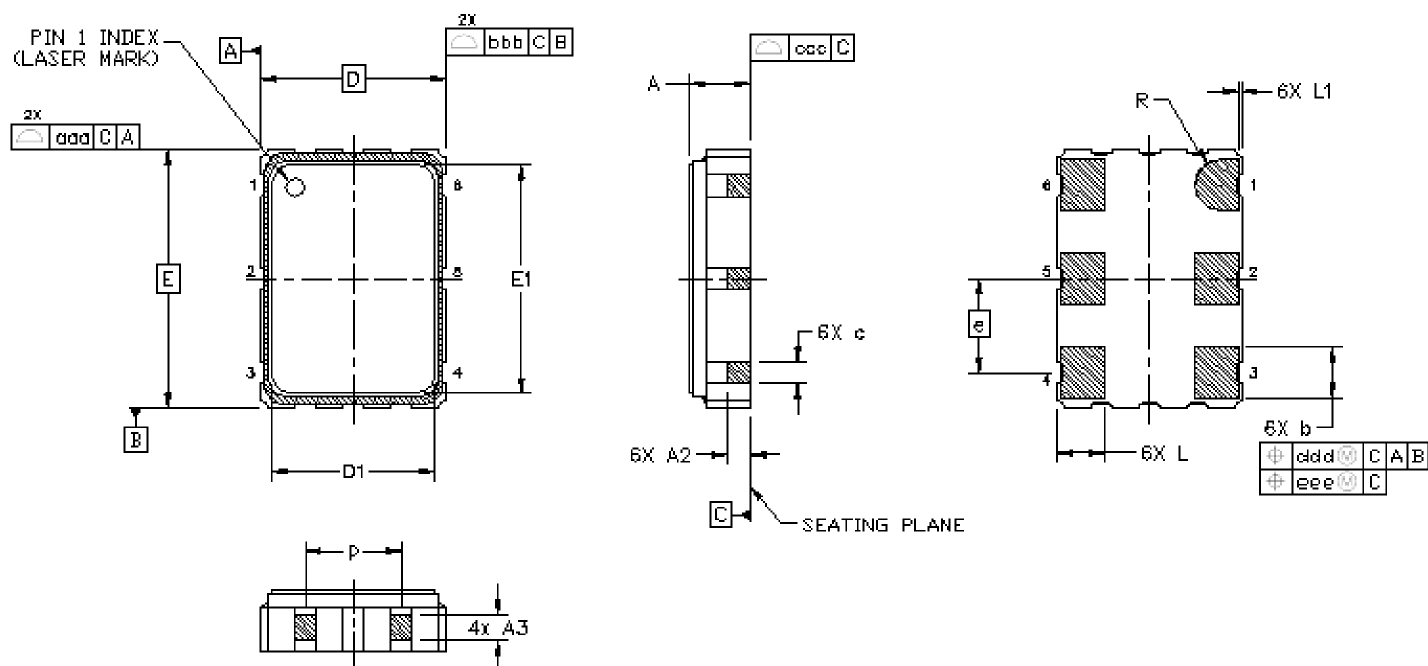


Figure 5.1. Si541 (5×7 mm) Outline Diagram

Table 5.1. Package Diagram Dimensions (mm)

Dimension	Min	Nom	Max	Dimension	Min	Nom	Max
A	1.13	1.28	1.43	L	1.17	1.27	1.37
A2	0.50	0.55	0.60	L1	0.05	0.10	0.15
A3	0.50	0.55	0.60	p	1.70	—	1.90
b	1.30	1.40	1.50	R		0.70 REF	
c	0.50	0.60	0.70	aaa		0.15	
D		5.00 BSC		bbb		0.15	
D1	4.30	4.40	4.50	ccc		0.08	
e		2.54 BSC		ddd		0.10	
E		7.00 BSC		eee		0.05	
E1	6.10	6.20	6.30				

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

5.2 Package Outline (3.2×5 mm)

The figure below illustrates the package details for the 3.2×5 mm Si541. The table below lists the values for the dimensions shown in the illustration.

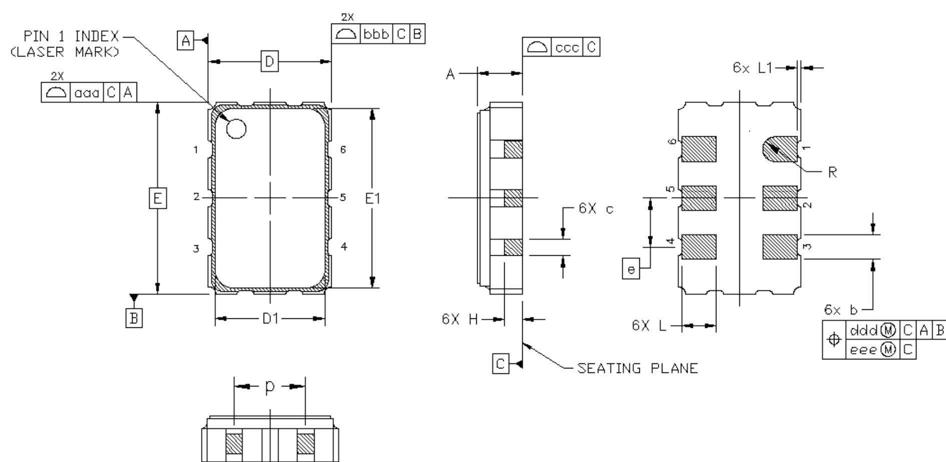


Figure 5.2. Si541 (3.2×5 mm) Outline Diagram

Table 5.2. Package Diagram Dimensions (mm)

Dimension	Min	Nom	Max
A	1.06	1.17	1.33
b	0.54	0.64	0.74
c	0.35	0.45	0.55
D		3.20 BSC	
D1	2.55	2.60	2.65
e		1.27 BSC	
E		5.00 BSC	
E1	4.35	4.40	4.45
H	0.45	0.55	0.65
L	0.80	0.90	1.00
L1	0.05	0.10	0.15
p	1.36	1.46	1.56
R		0.32 REF	
aaa		0.15	
bbb		0.15	
ccc		0.08	
ddd		0.10	
eee		0.05	

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

5.3 Package Outline (2.5x3.2 mm)

The figure below illustrates the package details for the 2.5x3.2 mm Si541. The table below lists the values for the dimensions shown in the illustration.

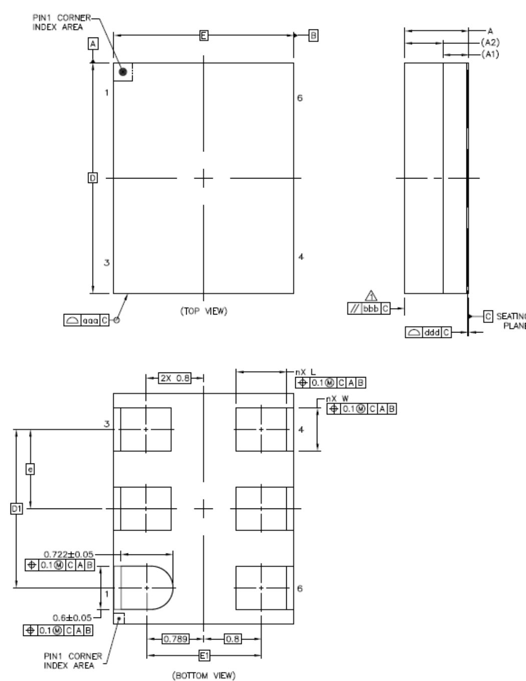


Figure 5.3. Si541 (2.5×3.2 mm) Outline Diagram

Table 5.3. Package Diagram Dimensions (mm)

Dimension	Min	Nom	Max
A	0.90	0.95	1.00
A1		0.36 REF	
A2		0.53 REF	
W	0.55	0.60	0.65
D		3.2 BSC	
E		2.5 BSC	
e		1.10 BSC	
L	0.65	0.70	0.75
n		5	
D1		2.2 BSC	
E1		1.589 BSC	
aaa		0.10	
bbb		0.10	
ddd		0.08	

Notes:

1. The dimensions in parentheses are reference.
2. All dimensions in millimeters (mm).
3. Dimensioning and Tolerancing per ANSI Y14.5M-1994.

6. PCB Land Pattern

6.1 PCB Land Pattern (5×7 mm)

The figure below illustrates the 5×7 mm PCB land pattern for the Si541. The table below lists the values for the dimensions shown in the illustration.

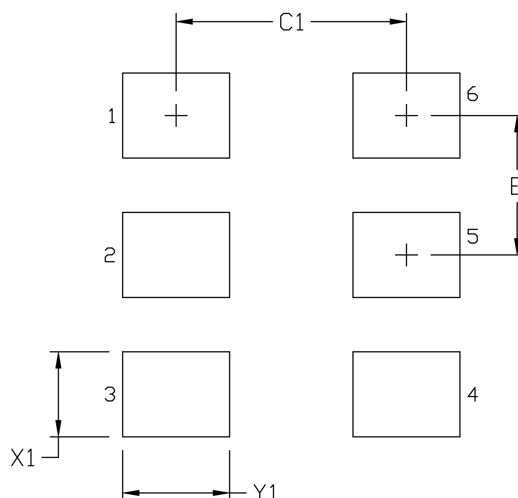


Figure 6.1. Si541 (5×7 mm) PCB Land Pattern

Table 6.1. PCB Land Pattern Dimensions (mm)

Dimension	(mm)
C1	4.20
E	2.54
X1	1.55
Y1	1.95

Notes:

General

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 1:1.

Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.2 PCB Land Pattern (3.2×5 mm)

The figure below illustrates the 3.2×5.0 mm PCB land pattern for the Si541. The table below lists the values for the dimensions shown in the illustration.

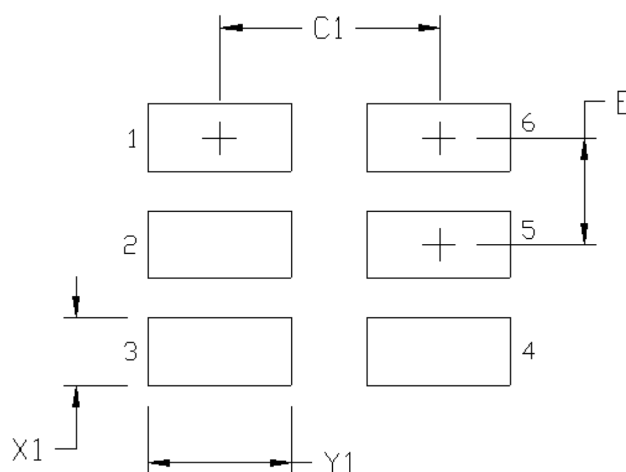


Figure 6.2. Si541 (3.2×5 mm) PCB Land Pattern

Table 6.2. PCB Land Pattern Dimensions (mm)

Dimension	(mm)
C1	2.60
E	1.27
X1	0.80
Y1	1.70

Notes:

General

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 1:1.

Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.3 PCB Land Pattern (2.5×3.2 mm)

The figure below illustrates the 2.5×3.2 mm PCB land pattern for the Si541. The table below lists the values for the dimensions shown in the illustration.

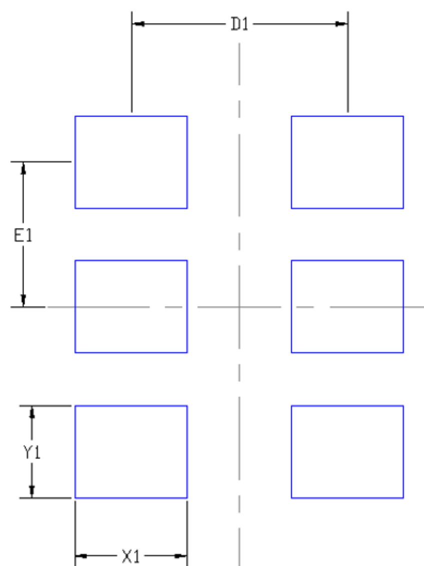


Figure 6.3. Si541 (2.5×3.2 mm) PCB Land Pattern

Table 6.3. PCB Land Pattern Dimensions (mm)

Dimension	Description	Value (mm)
X1	Width - leads on long sides	0.85
Y1	Height - leads on long sides	0.7
D1	Pitch in X directions of XLY1 leads	1.639
E1	Lead pitch XLY1 leads	1.10

Notes: The following notes and stencil design are shared as recommendations only. A customer or user may find it necessary to use different parameters and fine-tune their SMT process as required for their application and tooling.

General

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05 mm.

Solder Mask Design

1. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

Stencil Design

1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 0.8:1 for the pads.

Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

7. Top Marking (5x7 and 3.2x5 Packages)

The figure below illustrates the mark specification for the Si541. The table below lists the line information.

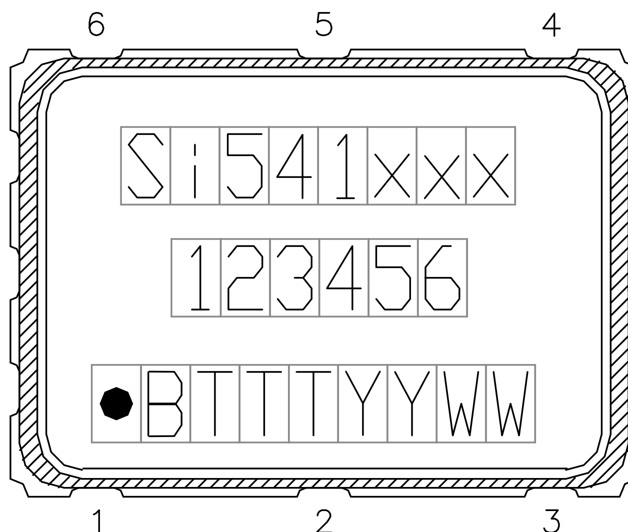


Figure 7.1. Mark Specification

Table 7.1. Si541 Top Mark Description

Line	Position	Description
1	1–8	"Si541", xxx = Ordering Option 1, Option 2, Option 3 (e.g. Si541AAA)
2	1–6	Frequency Code (6-digit custom code as described in the Ordering Guide)
3	**Trace Code**	
	Position 1	Pin 1 orientation mark (dot)
	Position 2	Product Revision (B)
	Position 3–5	Tiny Trace Code (3 alphanumeric characters per assembly release instructions)
	Position 6–7	Year (last two digits of the year), to be assigned by assembly site (ex: 2017 = 17)
	Position 8–9	Calendar Work Week number (1–53), to be assigned by assembly site

8. Top Marking (2.5x3.2 Package)

The figure below illustrates the mark specification for the Si541 2.5x3.2 package sizes. The table below lists the line information.

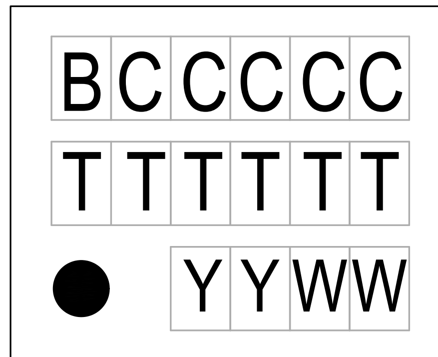


Figure 8.1. Mark Specification

Table 8.1. Si541 Top Mark Description

Line	Position	Description
1	1–6	B = Si541, CCCCC = Custom Mark Code
2	**Trace Code**	
	1–6	Six-digit trace code per assembly release instructions
3	Position 1	Pin 1 orientation mark (dot)
	Position 2–3	Year (last two digits of the year), to be assigned by assembly site (exp: 2017 = 17)
	Position 4–5	Calendar Work Week number (1–53), to be assigned by assembly site

9. Revision History

Revision 1.2

September 2020

- Updated Table 2.2, Powerup VDD Ramp Rate and LVDS Swing

Revision 1.1

November 2019

- Added 2.5x3.2 mm package option.

Revision 1.0

July 2018

- Added 20 ppm total stability option.

Revision 0.75

March 2018

- Added 25 ppm total stability option.

Revision 0.71

December 11, 2017

- Added 5x7 package and land pattern.

Revision 0.7

June 27, 2017

- Initial release.

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Silicon Laboratories Inc.
400 West Cesar Chavez
Austin, TX 78701
USA

http://www.silabs.com